

Notice of References Cited	Application/Control No. 10/537,584		Applicant(s)/Patent Under Reexamination DESTRO ET AL.	
	Examiner Anca Eoff		Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,698,373	12-1997	Fujikawa et al.	430/288.1
*	B	US-2007/0054220	03-2007	Heneghan, Michael	430/280.1
*	C	US-6,140,007	10-2000	Watanabe et al.	430/196
*	D	US-5,342,672	08-1994	Killey, Edward J.	428/32.64
*	E	US-5,770,115	06-1998	Misura, Michael S.	252/586
*	F	US-2001/0005619	06-2001	Hasebe et al.	438/487
*	G	US-2002/0057881	05-2002	Greer, Robert W. IV	385/128
*	H	US-2002/0146225	10-2002	Bulters et al.	385/125
*	I	US-5,030,548	07-1991	Fujikura et al.	430/281.1
*	J	US-4,540,746	09-1985	Roberts, Winston J.	525/408
*	K	US-3,935,163	01-1976	Spivack et al.	524/91
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.